

Title: SEMICONDUCTOR MEMORY  
DEVICE AND SEMICONDUCTOR  
MEMORY DEVICE CONTROL  
METHOD  
Inventor(s): Hiroyuki TAKAHASHI, et al.  
DOCKET NO.: 029471-0168

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[illegible]

FIG . 3

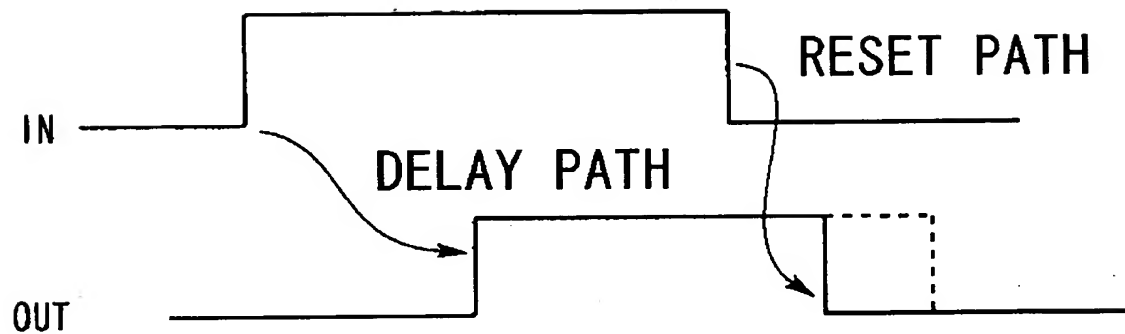


FIG . 4

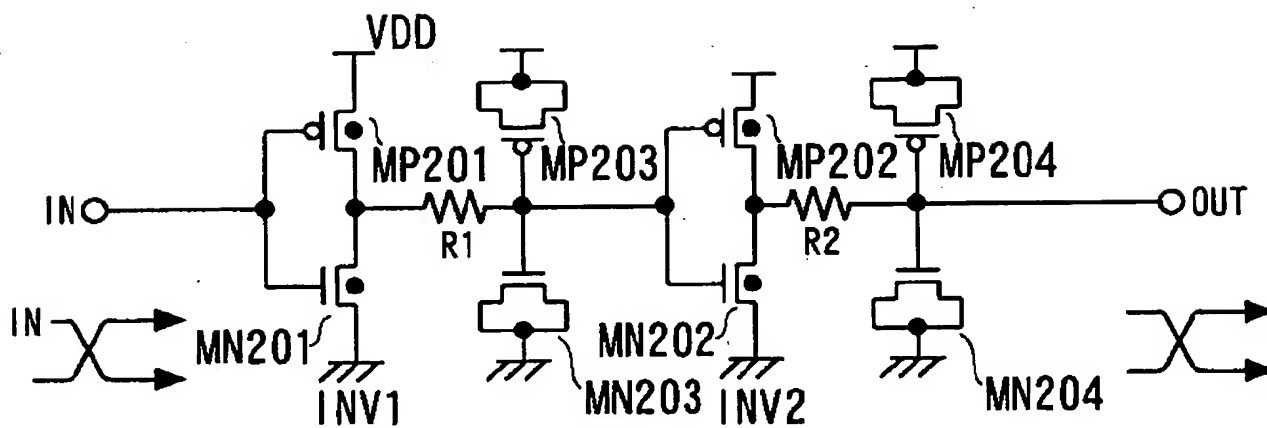
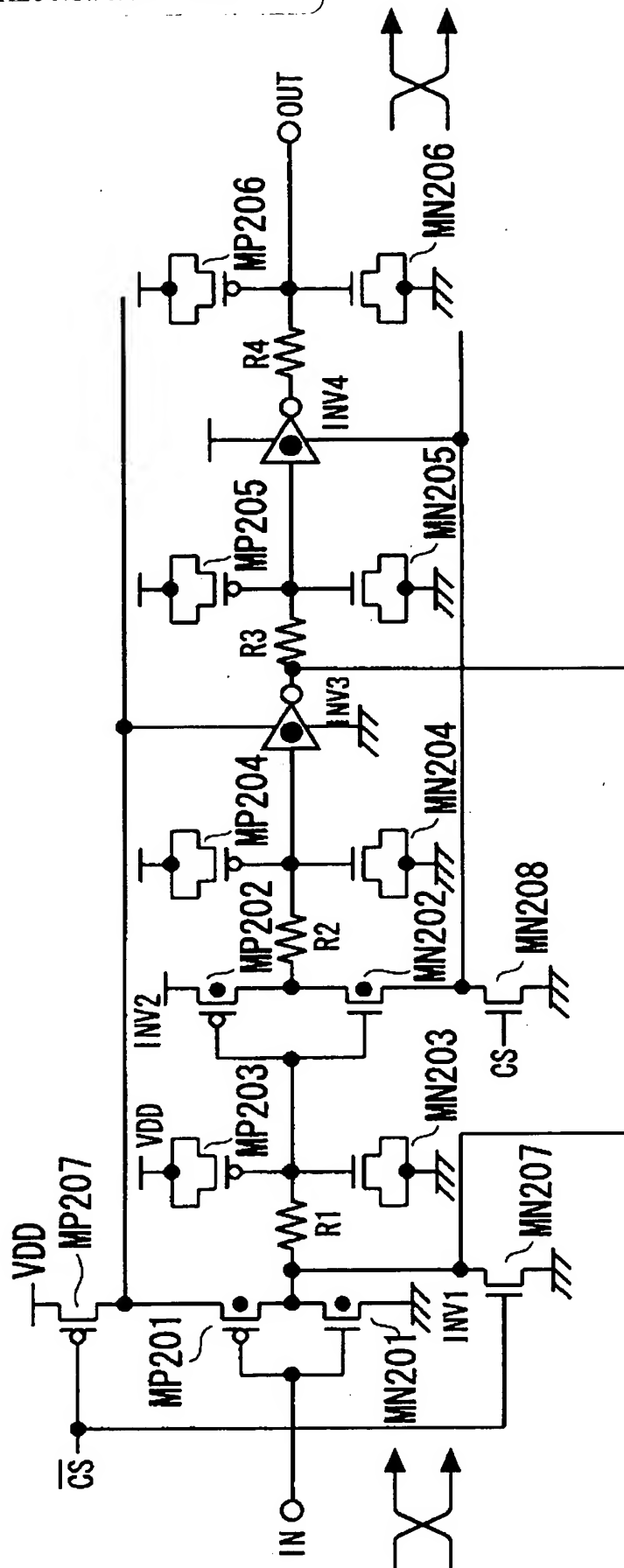


FIG. 5



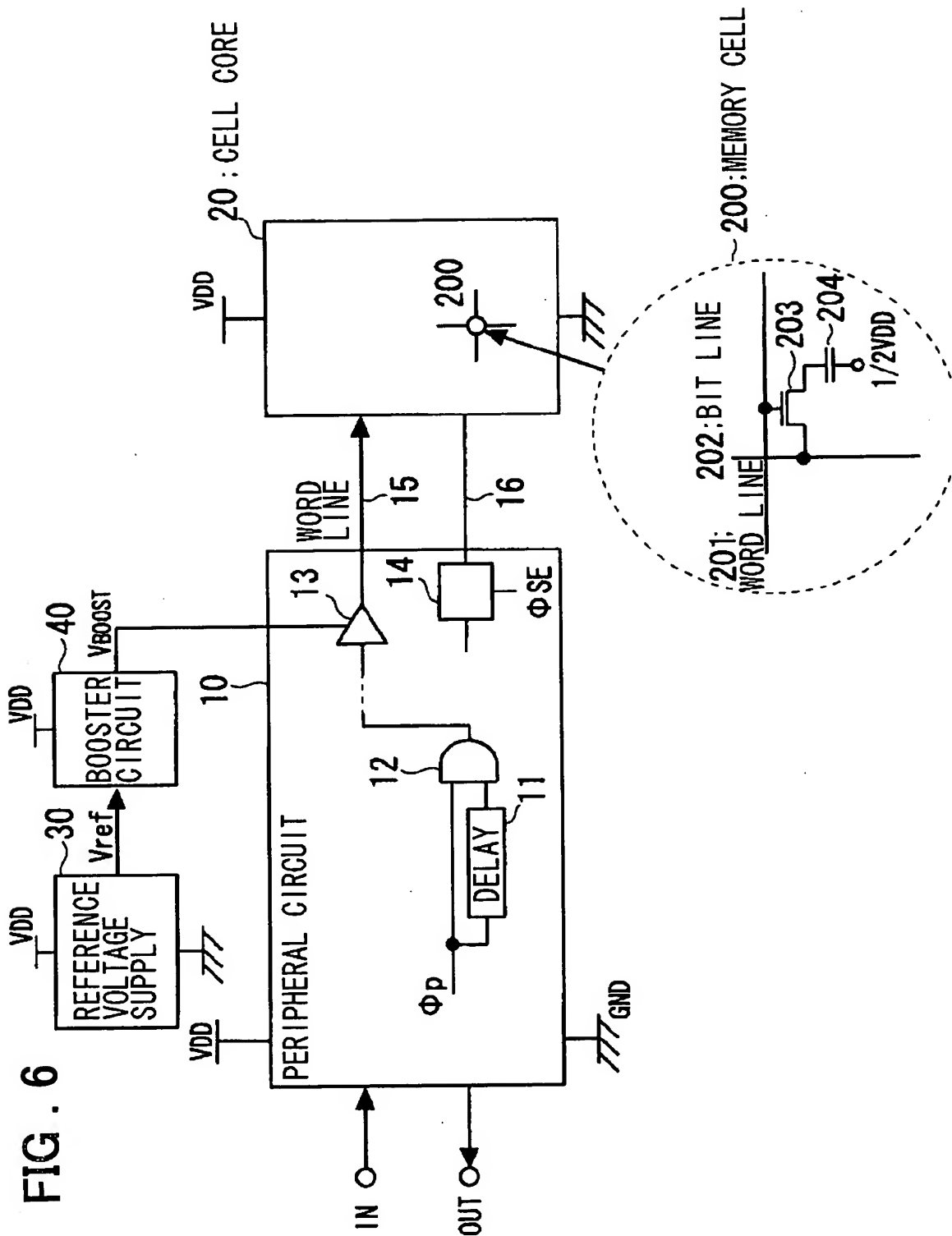


FIG . 7

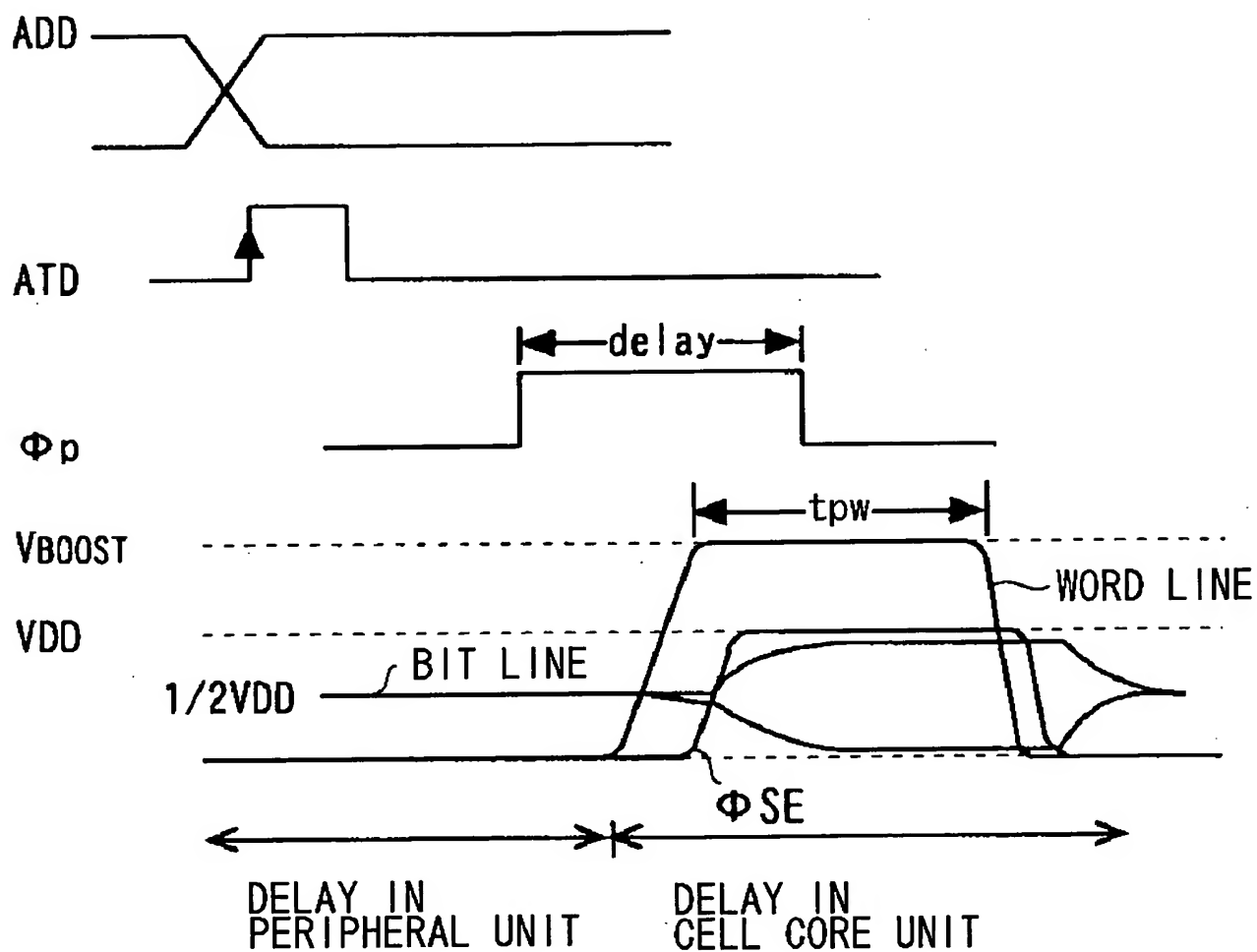


FIG . 8

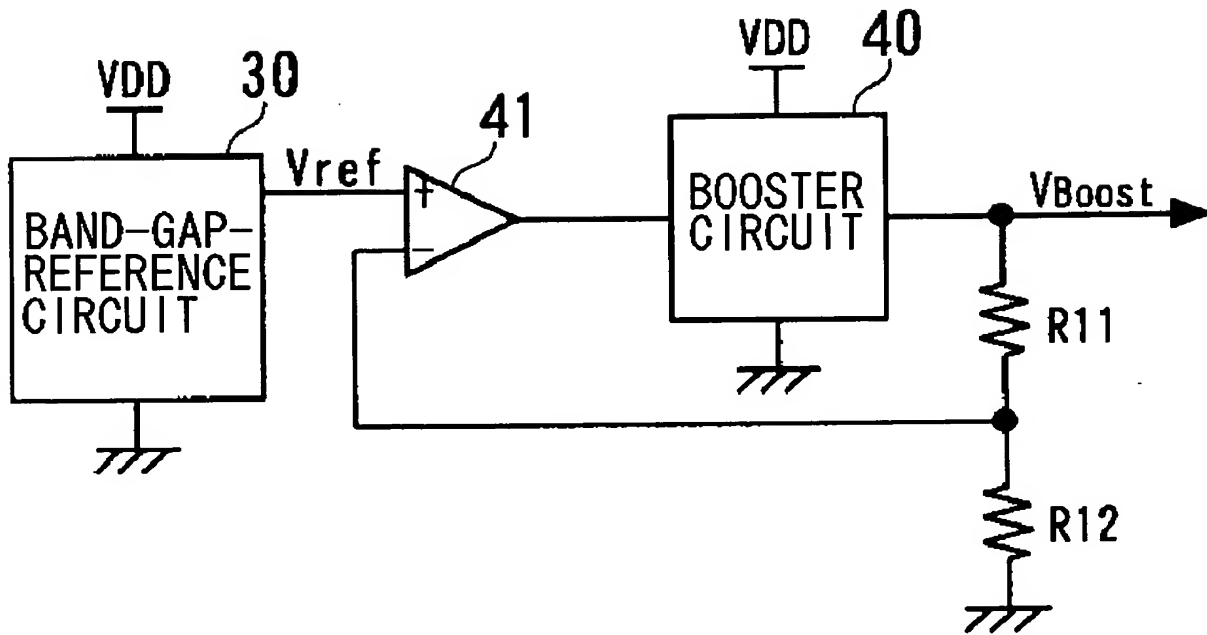




FIG . 9

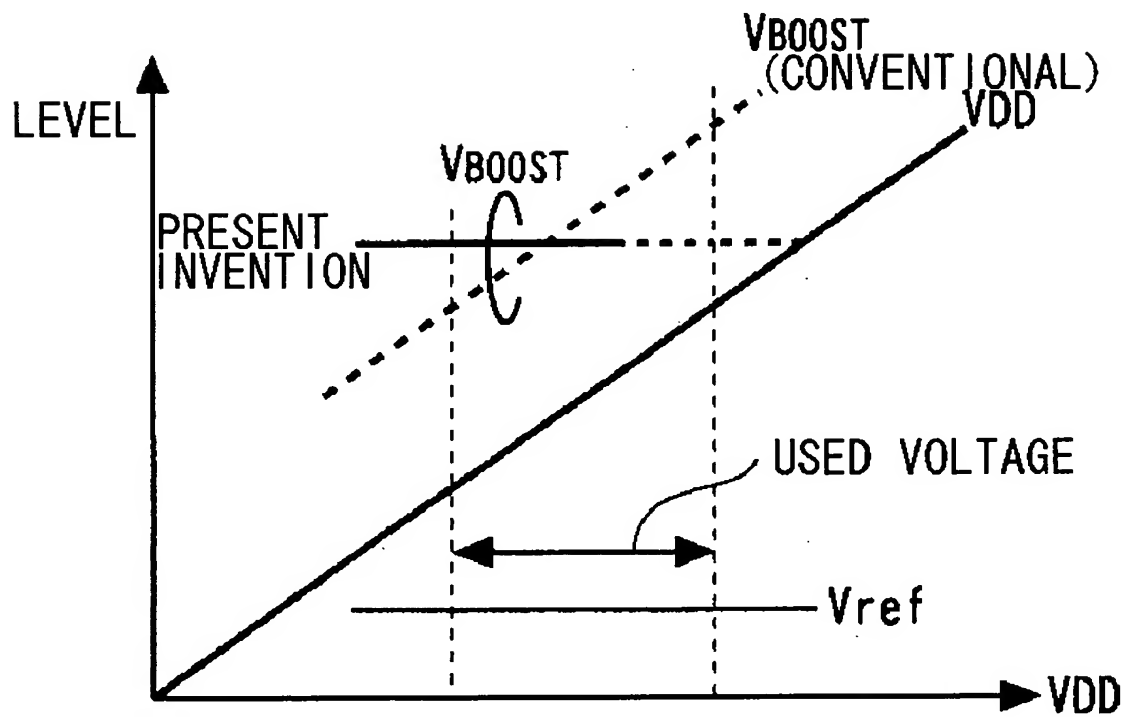


FIG . 10

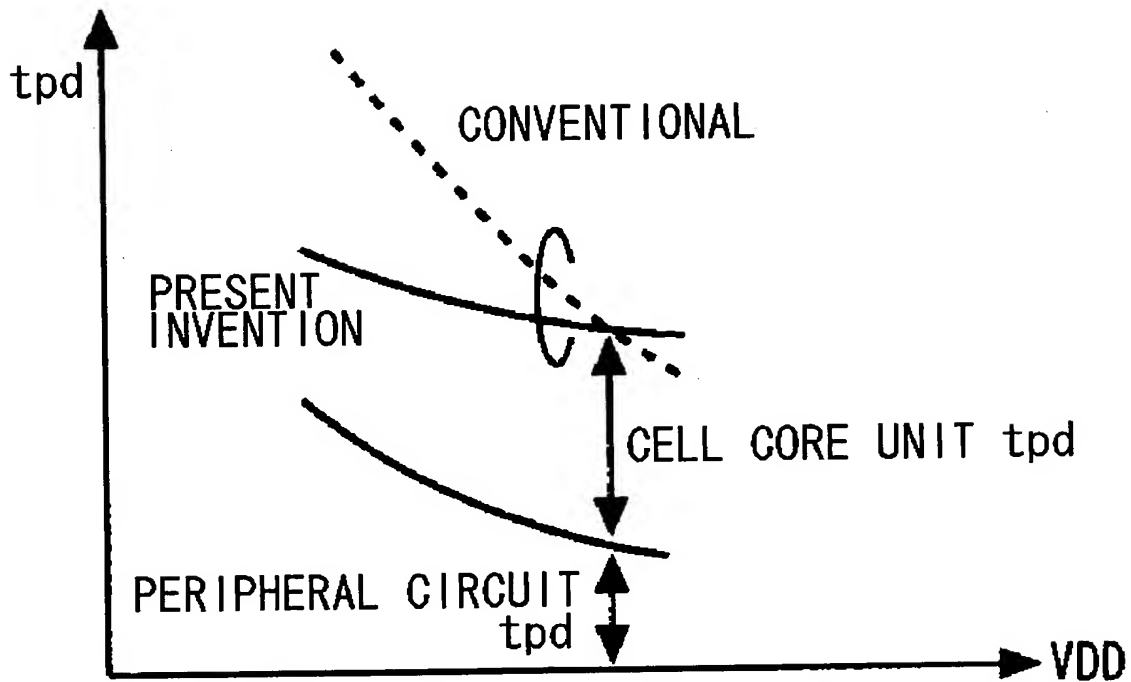


FIG . 11

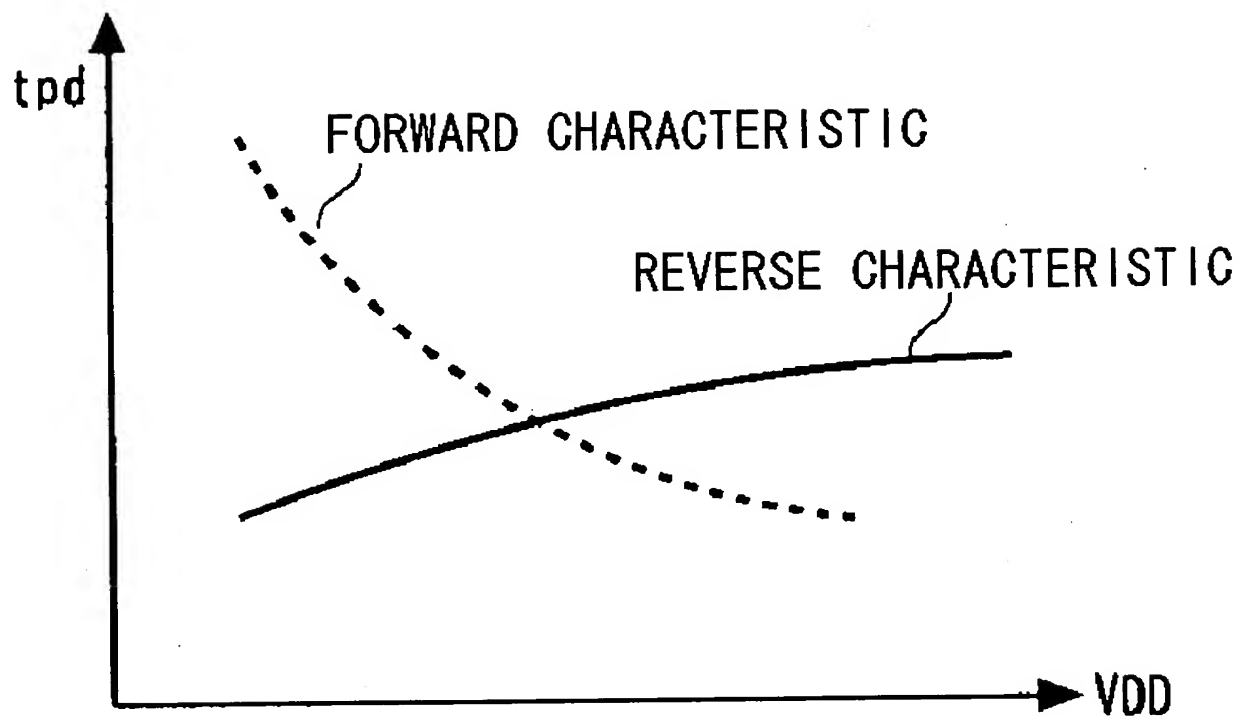


FIG . 12

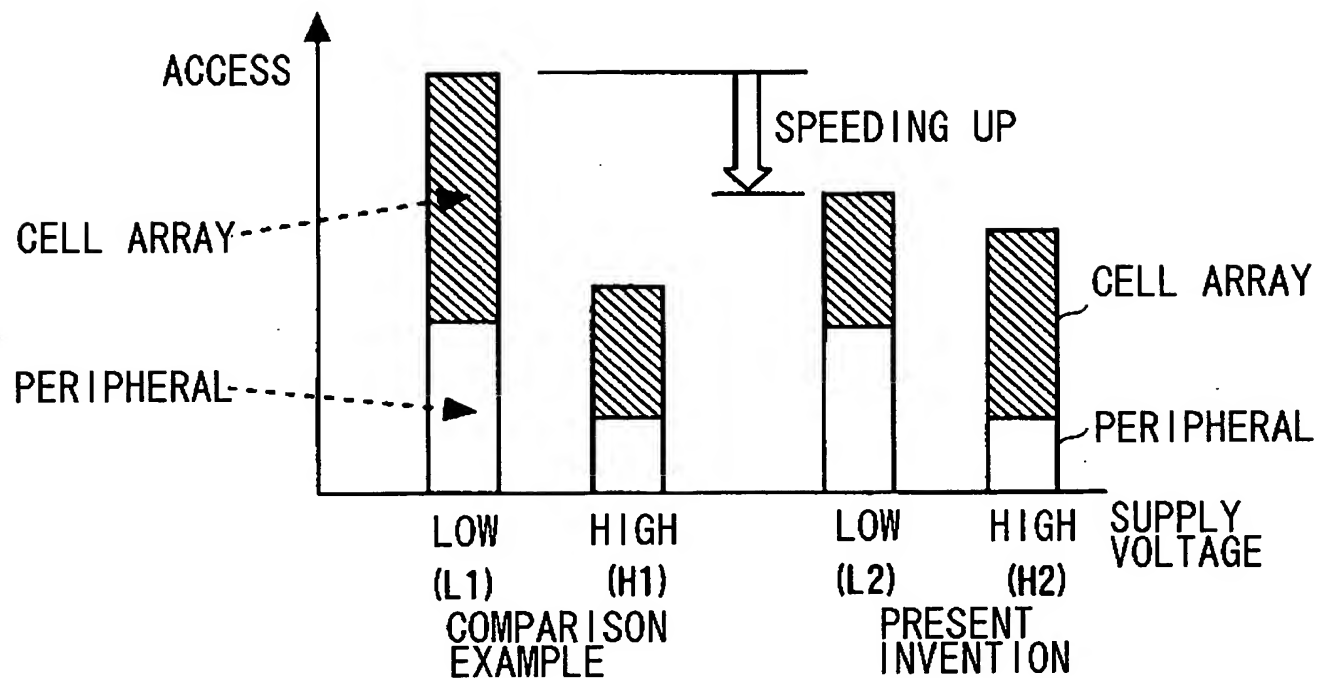
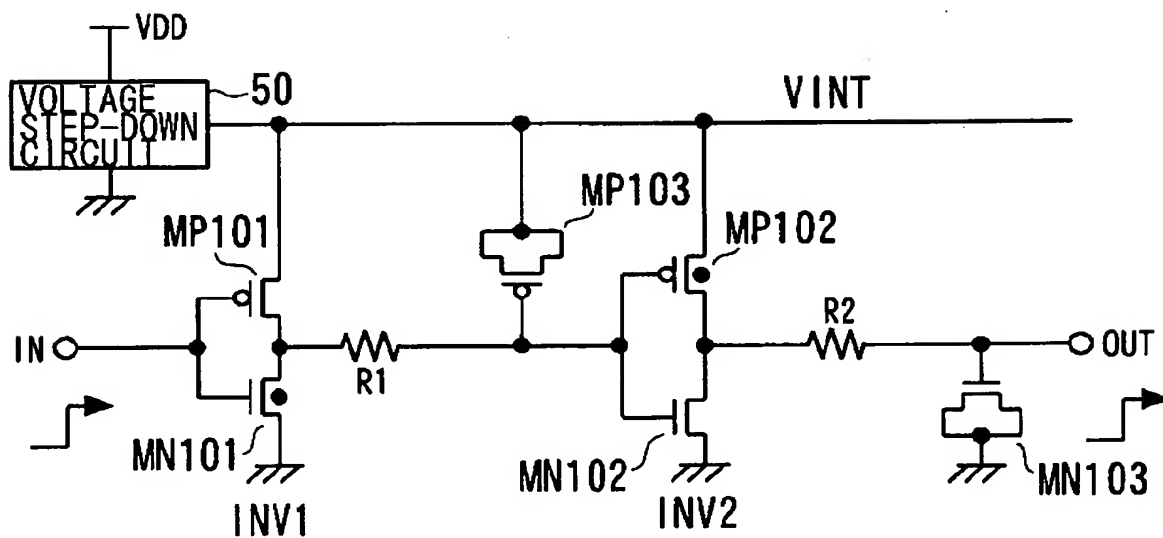


FIG. 13



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**FIG. 14**

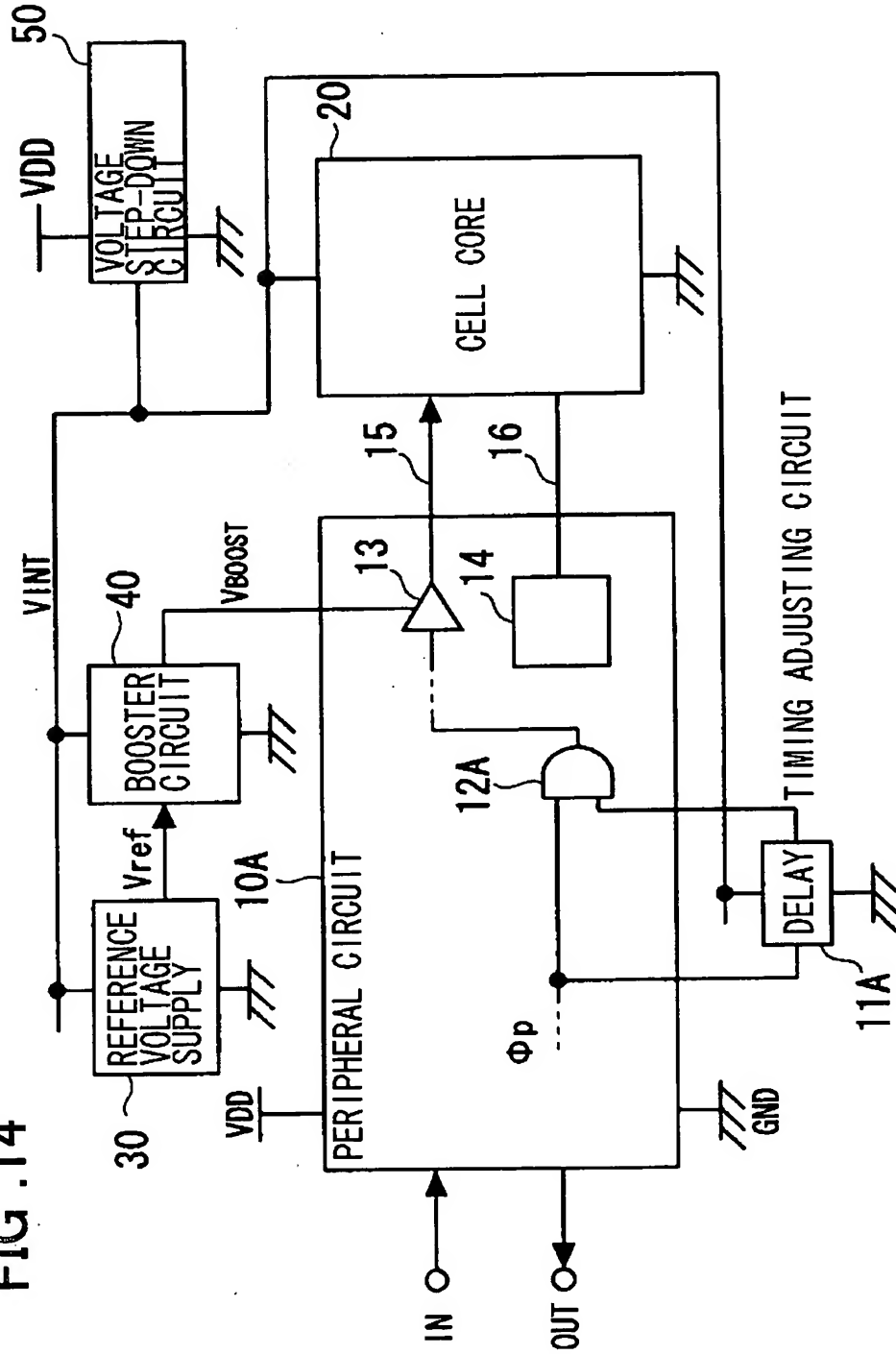


FIG. 15A PRIOR ART

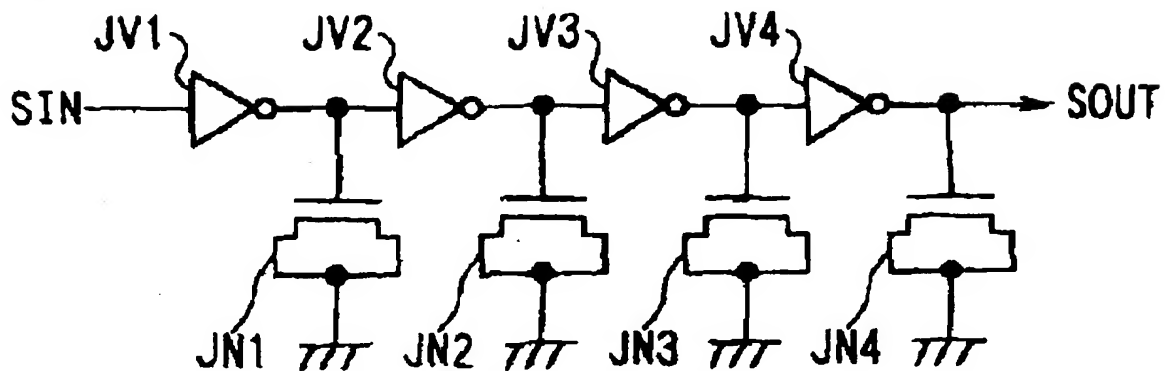


FIG. 15B PRIOR ART

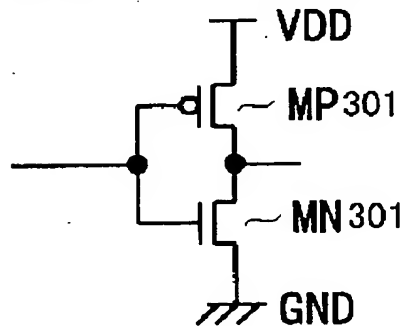


FIG . 16

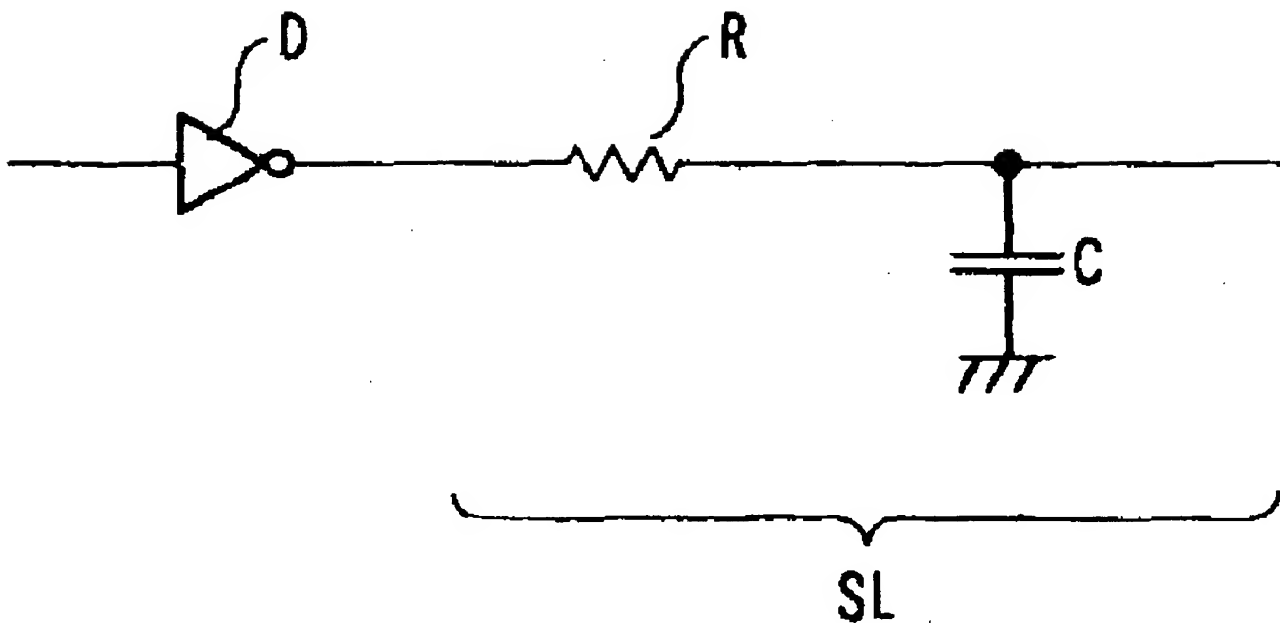




FIG . 17 PRIOR ART

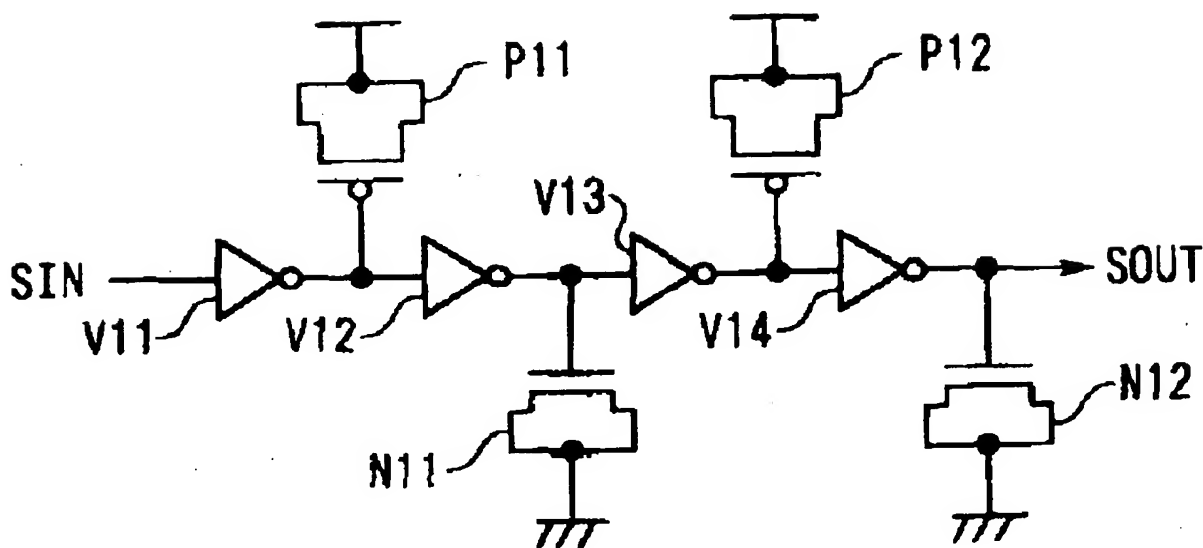


FIG . 18 PRIOR ART

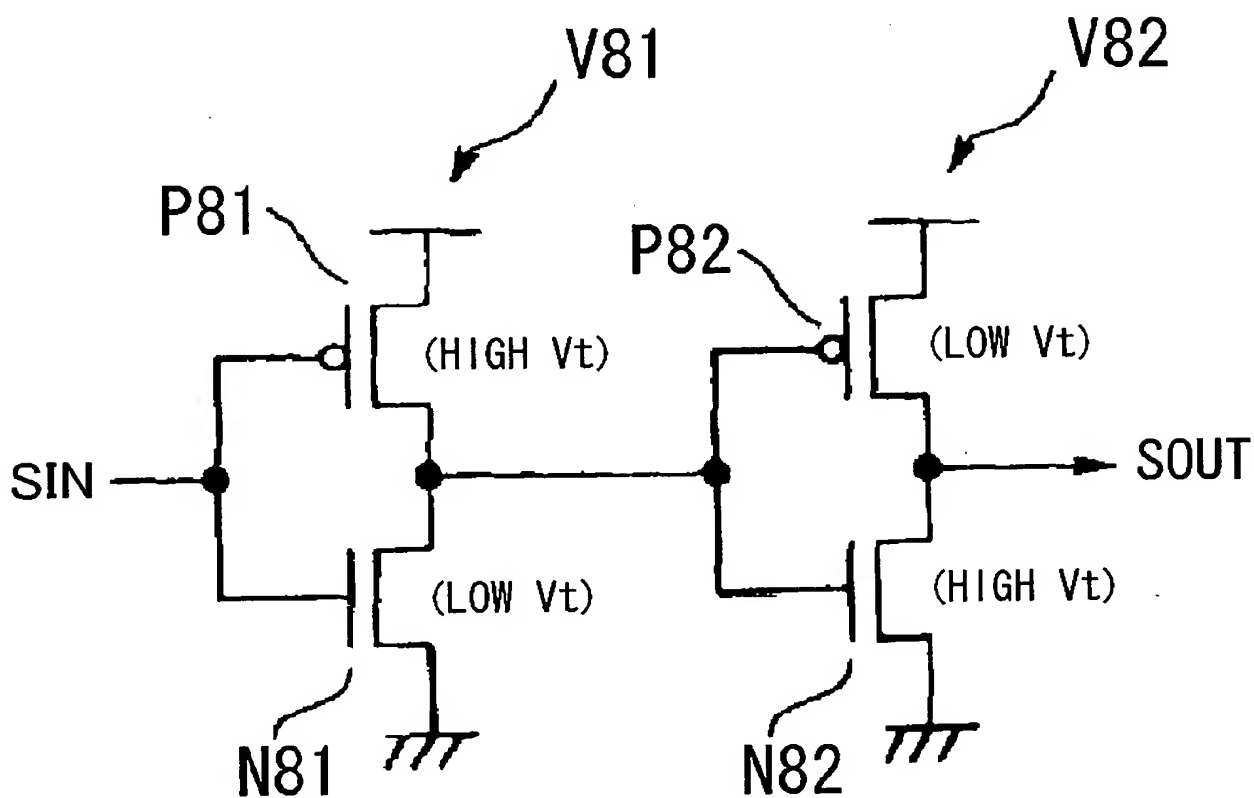
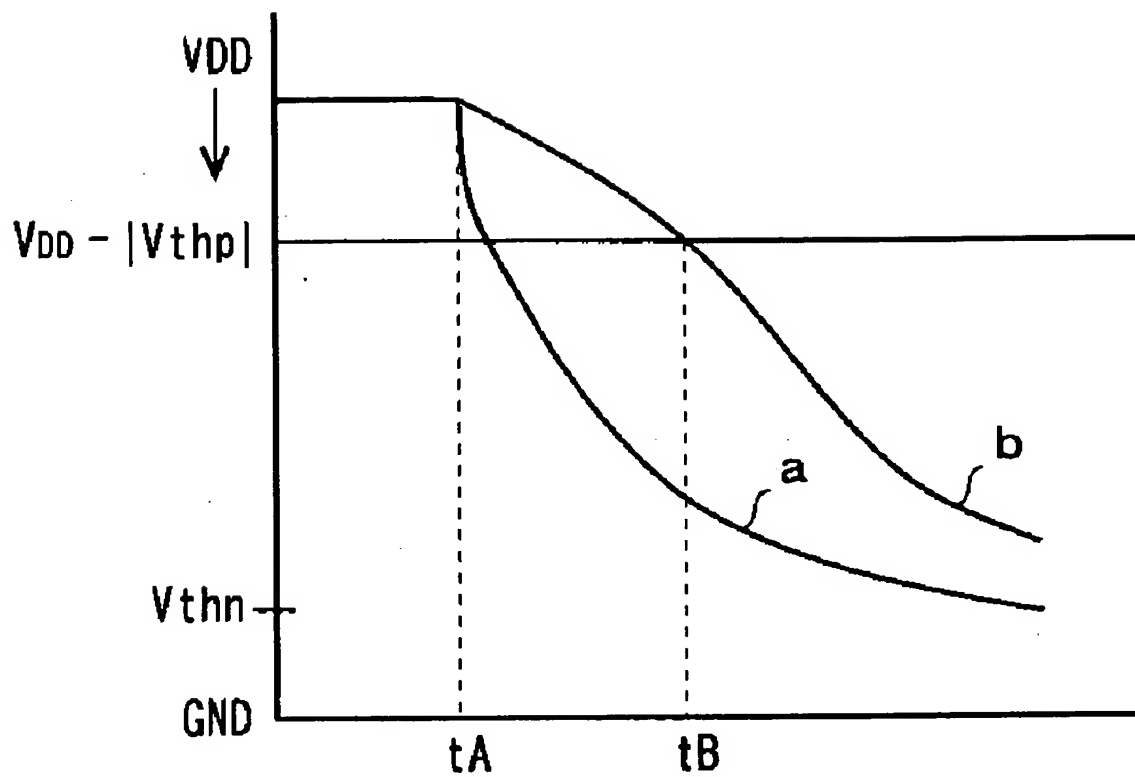


FIG. 19



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